

Search Notes**Application/Control No.**

10/564,086

Examiner

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Applicant(s)/Patent under Reexamination

BIAIS, FRANCOIS

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	214	2/15/2006	HN
310	215	2/15/2006	HN
310	216	2/15/2006	HN
310	52	2/15/2006	HN
310	54	2/15/2006	HN
310	58	2/15/2006	HN
310	64	2/15/2006	HN
update All 6/22/07 HN			
Search			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner